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		APPLICANT HARRIS ET AL.	
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EXAMINER INITIALS	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
ME	5 8 5 0 1 1 8	12/98	TODA			
J	5 8 3 1 4 9 2	11/98	SOLIE			
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	5 8 1 8 3 1 0	10/98	SOLIE			

FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	
ME	1 9 7 0 6 4 86	08/98	FED. REF. GERMANY			

ME		Streibl, M. et al. "SAW Tomography-Spatially Resolved Charge Detection by SAW in Semiconductor Structures for Imaging Applications", 1999 IEEE Ultrasonics Symposium Proceedings. International Symposium (Cat. No. 99CH 37027).
ME		1999 IEEE Ultrasonics Symposium, Proceedings. International Symposium. Caesars Tahoe, NV, U.S.A. 17-20 Oct. 1999, Pages 11-14, Vol. 1, XP002156577, 1999, Piscataway, NJ, U.S.A., IEEE, U.S.A., ISBN: 0-7803-5722-1

EXAMINER	DATE CONSIDERED
ME	4-24-03

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